



IMPROVED SUBSTRATE ISOLATION FOR ANALOG/DIGITAL IC CHIPS

1c978 U.S. PRO
09/01/035
07/23/01

Field of the Invention

This invention relates to integrated circuit devices with mixed signal components, e.g. analog and digital sections in the same IC substrate.

Background of the Invention

5 Isolation of electrical signals in IC devices has been addressed in the prior art, and a variety of approaches have been developed. Complete isolation has been achieved in power ICs with dielectrically isolated structures. This approach is effective, but costly, and it consumes significant chip area. Junction isolation, i.e. guard rings, is the technique of choice in densely packed VLSI devices.

10 Junction isolation is effective in blocking stray signals that propagate in the vicinity of the surface of the device. However, in ICs that are formed in epitaxial material, where the epitaxial layer is grown on a low resistivity substrate, an additional stray signal path extends vertically through the epi layer and into the low resistivity substrate. Once the signal reaches the substrate it can stray 15 unimpeded to any region of the chip. A proposal for dealing with interference in the substrate is to increase the resistivity of the substrate. Silicon on sapphire (SOS) and similar technologies have been developed which provide a high degree of isolation, but these types of wafers are more difficult to process and are not economical for many applications.

20 Another approach to IC isolation that was explored in the early 1980s was

the use of trenches between circuit components. V-groove trenches were found to consume excessive chip area. The advent of effective anisotropic plasma etching techniques, with which narrow trenches a few microns deep could be routinely formed, was also proposed for isolation. Techniques involving 5 trenches of either kind required backfilling to allow further planar processing, and were, overall, complex and expensive.

Some of these approaches have been combined in principle to produce an isolation technique called triple well isolation. This approach uses a blanket subsurface implant which extends beneath multiple wells. Triple well isolation 10 has been found to be efficient and cost effective. See "Simulation Techniques and Solutions for Mixed-Signal Coupling in Integrated Circuits" by Nishath K. Verghese, Timothy J. Schmerbeck and David J. Allstot, Second Edition, Kluwer Academic Publishers, 1995.

Recent advances in IC design and fabrication make possible the 15 integration of analog and digital circuits on the same IC chip. However, the analog signals are susceptible to interference and the presence of digital signals, or high level analog signals which swing the full voltage range, in the vicinity of analog components allows the digital interference to couple directly into the analog sections of the IC chip. The use of triple well isolation in these ICs is 20 ineffective since the isolation implant, which is typically tied to the voltage of the digital wells, i.e. the digital V_{DD} , actually couples directly the digital voltage swings into the analog wells.

Use of triple well regions within analog circuitry can be problematic even if the triple well region is tied to analog V_{DD} because analog circuits usually contain isolated N regions containing p-channel devices that are meant to be tubbed to some node other than V_{DD} . Since all of the NTUB regions within a 5 triple well region get connected together through the buried layer, existing analog circuitry would have to be redesigned to make it compatible with triple well. Thus, one advantage of the inventive scheme is that analog circuitry that was designed for an analog-only chip with no isolation scheme can be placed onto a mixed analog/digital chip without being redesigned.

10 **Summary of the Invention**

We propose an isolation technique for analog/digital subcircuits in a single chip implementation which uses a relatively simple modification of the triple well isolation technique. Having recognized that in triple well isolated circuits using both digital and analog sections the triple well implant channels 15 noise throughout the chip, the triple well deep implant in our modified isolation technique is selectively made just beneath the wells containing digital circuits. Thus only the portions of the chip that operate at digital V_{DD} are isolated with the triple well implant.

Brief Description of the Drawing

20 Fig. 1 is a plan view of a portion of an analog/digital multicircuit chip with selective triple well isolation according to the invention;

Fig. 2 is a sectional view through 2 - 2 of Fig. 1;

Fig. 3 is a schematic representation of the digital device array section of the mixed digital/analog chip;

Fig. 4 is a schematic representation of the analog device array section of the mixed digital/analog chip; and

5 Fig. 5 is a schematic representation of the digital device array section of the mixed digital/analog chip showing an n-well resistor integrated in the digital device array section.

Detailed Description

The use of selective triple well isolation according to the invention is 10 shown in Fig. 1. A plan view of a portion of a combined analog/digital integrated circuit chip is shown at 11. In the arrangement of Fig. 1, the digital and analog circuit layout has a "noisy" subcircuit, i.e. digital circuit, formed in digital tub 14 and a "sensitive" subcircuit, i.e. analog circuit, formed at 21, 22 in the analog section. For convenience in illustrating the invention the actual transistor 15 devices are not shown. Typically these comprise CMOS transistor arrays in both the digital tub and the analog tub. While the combination of analog and digital circuits is the most likely, and is chosen for illustration, the combination could also consist of or comprise analog circuit subsections with high level analog signal interference between them. The n-tub (usually n- material) implant for 20 the digital devices is shown at 12, encircling p-region (substrate region) 14. A portion 15 of p-region 14 is dedicated to n-channel digital devices. N-tub 16 is provided for p-channel digital devices. The site 15 for the n-channel digital

devices is shown located beside the n-tub 16, but other locations within p-region 14 are equally effective. The n-type triple well isolation region is tied to the digital V_{DD} . The n-tub 16 is also tied to the digital V_{DD} .

Also provided in the digital device section 14 is a site for an n-well 5 resistor. In the typical digital circuit, many resistors are used. However, unlike the transistor devices in the digital section, the resistor cannot be tied to V_{DD} . Therefore resistor 18 is segregated from the triple well isolated regions by deep surface implant 17 but, as will be seen, the deep triple well subsurface implant is omitted from the resistor site. The resistor is effectively formed in substrate 11. 10 The n-resistor is shown as a strip but may also be a serpentine n-type region. Resistor contacts (not shown) are formed at the ends of the resistor strip.

The analog devices are formed in p-type substrate regions shown in Fig. 1 to the right of the digital device region 14. The analog devices typically comprise 15 CMOS transistor pairs, with the p-type transistors formed in n-tub 21 and the n-type transistors formed in the p-substrate at location 22. Again, other spatial configurations may be used. As shown in these figures the analog devices are formed directly in the p-substrate, which is acceptable if the doping level of the substrate is appropriate. If a different level of doping is desired for the analog device array, a p-tub may be provided.

20 The triple well isolation regions can be seen in better perspective in Fig. 2, which is a section view through 2 - 2 of Fig. 1. The deep implant that completes the triple well isolation is shown at 23. The omission of a deep implant

underneath resistor 18 in the digital device section is also evident.

It will be appreciated by those skilled in the art that the features in the drawings are not to scale. For example, the features incorporated in the substrate, e.g. impurity regions, are shown as having dimensions that are overly 5 large compared with the thickness of the substrate. Accordingly, substrate 11 is shown broken to indicate that it extends substantially further down the page of the drawings. A typical silicon wafer may have a thickness of the order of 500 μm or more, while a conventional impurity region has a depth of less than 10% of that thickness.

10 Referring to Fig. 2, substrate 11 is a silicon substrate, only a portion of which is shown. The deep impurity region 23 can be formed by high energy ion implantation or by the so-called buried collector technique in which a selective surface implant is made for the isolation regions, and these regions are then "buried" by growing an epitaxial layer over the implanted wafer.

15 N-type wells 16 and 21 are formed by deep implants and drive in the conventional way. The n-wells are typically doped with phosphorus, and have a concentration in the range 10^{15} - $10^{17}/\text{cm}^3$. They may be formed using an implant drive at 1000 - 1200 $^{\circ}\text{C}$ for 10 - 660 minutes. The depth of the wells may vary but should be deep enough to intersect the buried isolation region 23. A useful range 20 for the depth of the isolation region below the wafer surface is 2 - 10 μm .

The p-wells 15 and 22 (Fig. 1) may use the substrate doping or may be more heavily doped using boron doping at a concentration of 10^{15} - $10^{17}/\text{cm}^3$, and

a drive at 1000 - 1200 °C for 10 - 660 minutes. The arrangement shown in Fig. 1, with alternating p-wells and n-wells is the usual case. However, complementary structures can also be formed with other sequences, e.g. multiple n-wells alternating with multiple p-wells. Techniques for forming complementary wells 5 are well known to those skilled in the art and need not be described in detail here.

The triple well isolation device of the invention is shown with more device detail in Figs. 3 and 4, with the digital devices shown in Fig. 3, and the analog devices shown in Fig. 4. It should be understood that Figs. 3 and 4 show 10 parts of the same chip substrate 41. In Fig. 3, a pair of CMOS transistors for the digital circuit is shown formed in substrate 41, with the p-channel transistor at 42 and the n-channel transistor at 43. The source and drain p-regions 45 of transistor 42 are formed in n-tub 46, with the gate shown at 48. The corresponding complementary transistor 43 is shown here formed in isolated 15 p-substrate region 44 with source and drain n-regions 51 and gate 52. The triple well isolation for the digital circuit comprises deep surface implants 54 and buried region 55.

The analog section of the chip is shown in Fig. 4, with p-channel transistor 61 and n-channel transistor 62 formed in substrate 41. The p-channel transistor 20 has p-type source and drain regions 64 formed in n-tub 65, with the gate at 66. The corresponding n-channel device is shown with n-type source and drain regions 67, and gate 68. These devices are made by the steps of forming the

silicon gate over selected n-wells and p-wells or substrate regions, and implanting the source and drain regions as shown. Suitable doping levels for source and drain regions is in the range 10^{18} - 10^{20} /cm³.

It will be apparent to those skilled in the art that complementary elements of the device structure can be exchanged with regard to impurity type.

As indicated earlier, the digital circuits frequently include n-well resistors that are simple strip resistors formed of n-well (usually n⁻) material. However, it is important that they, unlike the digital transistors, be isolated from the digital V_{DD} . Consequently they should be formed in the same manner as the analog devices, i.e. separated from the deep triple well isolation implant. This is illustrated in Fig. 5, where resistor 71 is formed in digital device section, i.e. with digital devices on both sides, but where the deep isolation implant 55 does not extend beneath the resistor 71. For convenience, the n-region for the resistor may be formed in the same step as the surface implants for the triple well isolation, in which case the resistor implant resembles the surface triple well implants 54 as shown in Fig. 5.

As is well known, the digital devices operate with a switched voltage that swings the full range at each operation from the on state to the off state, i.e. the digital drive voltage V_D steps from a first value V_{D1} , to a second value V_{D2} . The triple well isolation regions are tied to this voltage, V_D . The analog devices operate using voltage which is designated "V_A" here and in the appended claims, and may vary over a range of voltages between values V_{A1} and V_{A2} . The

reference voltage for the drive voltages, i.e. V_{SS} , are tied to the p-type substrate, in both sections, i.e. digital V_{SS} is tied to region 14 in Fig. 1, and analog V_{SS} is tied to substrate 11.

Various additional modifications of this invention will occur to those skilled in the art. All deviations from the specific teachings of this specification that basically rely on the principles and their equivalents through which the art has been advanced are properly considered within the scope of the invention as described and claimed.